Ab{initio calculation of Kerr spectra for sem i{in nite systems including multiple reections and optical interferences

A. Vemes

Center for Computational Materials Science,

Technical University Vienna, Gumpendorferstr. 1a, A {1060 Vienna, Austria

L.Szunyogh

Center for Computational Materials Science,

Technical University Vienna, Gumpendorferstr. 1a, A {1060 Vienna, Austria

Department of Theoretical Physics, Budapest University of Technology and Economics,

Budafoki ut 8, H {1521 Budapest, Hungary

P.W einberger

Center for Computational Materials Science,

Technical University Vienna, Gumpendorferstr. 1a, A {1060 Vienna, Austria

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Abstract

Based on Luttinger's formulation the complex optical conductivity tensor is calculated within the fram ework of the spin {polarized relativistic screened K orringa{K ohn {R ostoker m ethod for layered system s by m eans of a contour integration technique. For polar geometry and normal incidence ab{initio K err spectra of multilayer systems are then obtained by including via a 2 2 m atrix technique all multiple rejections between layers and optical interferences in the layers. Applications to $CoPt_5$ and $Pt_3 CoPt_5$ on the top of a semi(in nite fcc{Pt(111)} bulk substrate show good qualitative agreement with the experimental spectra, but dier from those obtained by applying the commonly used

two{media approach.

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I. IN TRODUCTION

Magneto-opticale ects not only provide a powerful tool in probing the magnetic properties of solids, [1{3] but are also of direct technological interest as phenomena to be used for high { density magneto (optical recording. [2,4] Up to now, however, realistic theoretical investigations were lacking, because band { structure methods using supercells, [5] cannot provide an adequate description of layered systems, for which special computational techniques such as the spin { polarized relativistic screened Korringa (Kohn (Rostoker (SKKR)) method have been designed. [6{8] Furtherm ore, the absorptive parts of the optical conductivity tensor as obtained from the inter(band contributions, [9] are not su cient for magneto(optical Kerr spectra calculations, since also the dissipative parts have to be known. Hence, in supercell type calculations, besides the necessity to use the K ram ers{K ronig relations, one has to include also the inter{band contributions by means of a sem i(em pirical D rude term. [10] Only recently a better scheme was developed by two of the present authors [11], in which a contour integration is used to obtain the com plex optical conductivity tensor as based Luttinger's form ula, [12] which in turn includes all inter{ and intra {band contributions. [13] C om bining this contour integration technique with the SKKR method, realistic inter{ and intra{layer complex optical conductivities can be obtained for layered system s.

Having evaluated the inter{ and intra{layer optical conductivities, them agneto{optical Kerr spectra can then be calculated by using a macroscopical model such as, e.g., the two{media approach. [14] Because the layered system contains more boundaries than just the interface between the vacuum and the surface layer, the two{media approach not fully includes the dynamics of the electrom agnetic waves propagation in such systems. Since the pioneering work of Abeles in 1950, [15] several methods are known in the literature [16,17] to treat multiple rejections and interferences using either a 2 2 matrix [18,19] or 4 4 matrix [20{22] technique. In the present paper the magneto{optical Kerr spectra of layered systems are evaluated for the most frequently used experimental set{up, namely polar geometry and normal incidence, by making use of the complex optical conductivity tensor and the 2 2 matrix technique.

In Section II the theoretical background is reviewed brie y. Computational aspects are then sum marized in Section III. In Section IV the two (media approach (Sect. IV A) and the applied

2 2 m atrix technique (Sect. IV C) are viewed as two di erent m acroscopic m odels of how to calculate m agneto {optical K err spectra of layered system s. Particular em phasis has been put in Sect. IV B on the construction of layer{resolved perm ittivities in term s of the (m acroscopic) m aterial equation w ithin linear response. This construction m ethod combined w ith the 2 2 m atrix technique, allows one to determ ine self{consistently layer{resolved perm ittivities, see Sect. IV C 4. As an illustration ab{initio K err spectra of Copt multilayer systems are presented and discussed in Section V. Finally, in Section VI the main results are summarized.

II. THEORETICAL FRAM EW ORK

A . Luttinger's form alism

The frequency dependent complex optical conductivity tensor ~ (!) can be evaluated starting from the well{known K ubo formula and using a scalar potential description of the electric eld. [23] However, by using the equivalent [24] vector potential description of the electric eld, one ends up with Luttinger's formula: [12]

$$\sim (!) = \frac{\sim (!) \sim (0)}{\sim ! + 1};$$
 (1)

with the current correlation function as given by [25]

~
$$(!) = \frac{i_{n}}{V} \frac{X}{\sum_{m=1}^{\infty} \frac{f(n) f(m)}{\sum_{m=1}^{\infty} J_{nm} J_{mn}} J_{nm} J_{mn}} :$$
 (2)

Here f () is the Ferm i{D irac distribution function, $_m$; $_n$ a pair of eigenvalues of the one{ electron H am iltonian, the J_{mn} are matrix elements of the electronic current operator (= x;y;z) and V the reference (crystalline) volume.

The positive in nitesimal implies the electromagnetic eld to be turned on at t=1 and hence describes the interaction of the system with its surrounding. [26] However, as can be seen from Eq. (2), can be also viewed as a nite life (time broadening, which accounts for all scattering processes at a nite temperature.

Luttinger's formula (1) and Eq. (2) have several advantages over the commonly used optical conductivity tensor formula of Callaway. [9] First of all, in contrast to the latter, Eq. (1)

B.Contour integration technique

Instead of evaluating the sum s in the expression for the current correlation function
(2) over eigenvalues of the one{electron H am iltonian, ~ (!) can be calculated by m eans of a contour integration in the complex energy plane.

For the selection of a particular contour , this technique [11] exploits the facts that with the exception of the M atsubara poles $z_k = "_F + i (2k - 1)_T (k = 0; 1; 2; ...; and_T = k_B T)$, [27] in both sem i(planes the Ferm i(D irac distribution function of complex argument f (z) is analytical [25] and is a real function for complex energies $z = " - i_J$ situated in (between two successive M atsubara poles. [28] The latter property of f (z), e.g., is exploited by using $j = 2N_{jT}$, where N_1 is the number of M atsubara poles included in in the upper sem i(plane and N_2 in the lower sem i(plane. [11]

By applying the residue theorem, it has been shown [11] that equivalently to Eq. (2) one has

such that

where $= \sim ! + i$ and the kernel

$$(z_1; z_2) = \frac{\sim}{2 \text{ V}} \text{ Tr } [J \ G \ (z_1) \ J \ G \ (z_2)];$$
 (5)

is related to the electronic G reen function G (z). The auxiliary quantity $(z_1; z_2)$ has already been used in residual resistivity calculations (!; T = 0) of substitutionally disordered bulk systems [29] and magneto {transport calculations of inhomogeneously disordered layered systems. [30] 0 nly recently, however, it has been shown, [13] that Eqs. (3) { (5) preserve all the advantages and features of Luttinger's formalism as was mentioned already above.

In the present paper, $\sim (z_1; z_2)$ is evaluated in terms of relativistic current operators [30] and the G reen functions provided by the spin {polarized relativistic SKKR m ethod for layered systems [6{8}]. The optical conductivity tensor of a multilayer system is then given [31] by

$$\sim (!) = \sum_{p=1 \text{ q= 1}}^{X^{N}} x^{pq} (!);$$
 (6)

with \sim^{pq} (!) referring to either the inter{ (p \in q) or the intra{layer (p = q) contribution to the optical conductivity tensor.

III. COM PUTATIONAL DETAILS

In addition to the number of M atsubara poles considered, the optical conductivity tensor depends also on the number of complex energy points n_z used in order to evaluate the energy integrals in Eqs. (3) and (4), on the number of K {points used to calculate the scattering path operators that de ne the G reen functions [7] and $^{\sim}$ (z $^{\sim}$! + i ;z) for a given energy z. Recently, the present authors have proposed two schemes to control the accuracy of these z{ and K{integrations. [32]

The rst of these schemes is meant to control the accuracy of the z{integrations along each contour part by comparing the results obtained from the Konrod quadrature [33,34], $K_{2n_z+1}^{\sim}$ (!), with those from the Gauss integration rule, $G_{n_z}^{\sim}$ (!). [35]0 n a particular part of the contour [32]

max
$$K_{2n_z+1}^{\sim}$$
 (!) $G_{n_z}^{\sim}$ (!) "z; (7)

is fullled for a given accuracy parameter $"_z$.

The other scheme refers to the cumulative special points method, [32] which permits to perform two{dimensional K {space integrations with arbitrary high precision. This method exploits the arbitrariness of the special points mesh origin. [36] For a given (arbitrary high) accuracy K the following convergence criterion has to apply

max
$$S_{n_i}^{\sim} (z^0; z) S_{n_{i-1}}^{\sim} (z^0; z)$$
", (8)

for any complex energy z on the contour or z_k M atsubara pole. Here $n_i=2^{i+2}n_0$ (n_0 2 N) is the number of divisions along each primitive translation vector in the two{dimensional K{space} and $z^0=z+$, z

In the present paper, the optical conductivity tensor calculations were carried out for T = 300 K, using a life{time broadening of 0:048 Ryd and N₂ = 2 M atsubara poles in the lower sem i{plane. Because the computation of ~ (!) does not depend on the form of the contour, [32] in the upper sem i{plane we have accelerated the calculations by considering N₁ = 37 M atsubara poles. The convergence criteria (7) and (8) were full led for $\mathbf{v}_z = \mathbf{v}_k = 10^{-3}$ a.u..

IV.MAGNETO {OPTICAL KERR EFFECT

In the case of the polar magneto {optical Kerre ect (PMOKE), [14] the Kerr rotation angle

$$_{K} = \frac{1}{2} \left(\begin{array}{cc} + \end{array} \right) \tag{9}$$

and the Kerrellipticity

$$\mathbf{v}_{K} = \frac{\mathbf{r}_{+} \quad \mathbf{r}}{\mathbf{r}_{+} + \mathbf{r}} \tag{10}$$

are given in terms of the complex reectivity of the right (+) and left (handed (() circularly polarized light

$$r = \frac{E^{(r)}}{F_{c}^{(i)}} = r e^{i}$$
 (11)

Here the complex amplitude of the rejected right and left {handed circularly polarized light is denoted by $E^{(r)}$ and that of the incident light by $E^{(i)}$; is the phase of the complex

re ectivity \mathbf{r} and $\mathbf{r} = \mathbf{j}\mathbf{r}$ j. Eqs. (9) and (10) are exact, which can be easily deduced from simple geometrical arguments. However, in order to apply these relations, one needs to make use of a macroscopic model for the occurring re-ectivities.

A.M acroscopic model I: the two{media approach

This simplest and most commonly used macroscopic model treats the multilayer system as a homogeneous, anisotropic, sem i{in nite medium, such that the incident light is rejected only at the boundary between the vacuum and the surface (top) layer.

In case of normal incidence the two $\{m \text{ edia approach provides an appropriate formula for the complex K errangle [14]}$

$$^{\sim}_{K} \qquad _{K} \qquad \dot{\mathbf{1}}^{\mathbf{n}}_{K} = \dot{\mathbf{1}}^{\mathbf{n}}_{\mathbf{n}} + \dot{\mathbf{n}}^{\mathbf{n}} ; \qquad (12)$$

which can be deduced from Eqs. (9) and (10) by assuming a small dierence in the complex rejectivity of the right { and left {handed circularly polarized light. Because Im \sim_{xy} (!) usually is almost a hundred times smaller than Re \sim_{xx} (!), see Ref. [13], the average complex refractive index of the right { and left {handed circularly polarized light is dominated by \sim_{xx} (!) and hence the following direct formula results from Eq. (12): [14]

with \sim (!) as given by Eq. (6). It should be noted that the \direct" formula in Eq. (13) was introduced by Reim and Schoenes [14] in order to extract the optical conductivity tensor elements \sim_{xx} (!) and \sim_{xy} (!) from experimental PMOKE data.

B.M acroscopic model II: layer{resolved permittivities

W ithin linear response theory [37] the Fourier transform ed m acroscopic m aterial equations, [38] averaged over the reference volume V, directly yields the total electric displacement

$$\frac{1}{V} \int_{V}^{Z} d^{3}r \, \mathcal{D} (x;!) = \frac{1}{V} \int_{V}^{Z} d^{3}r \, d^{3}r^{0} \sim (!;x;x^{0}) \, \mathcal{E} (x^{0};!) ; \qquad (14)$$

provided that the dielectric function $\sim (!; r; r^0)$ and the Fourier components of the electric eld $E'(r^0; !)$ are known.

U sing non {overlapping cells in con guration space (A tom ic Sphere Approximation (A SA), applied in the present approach), the reference volume can be written as

where N_k is the number of atoms per layer (the same 2D lattice has to apply for each layer p), N_k the total number of layers and p_k the volume of the ith atom ic sphere in layer p.

A ssum ing that plane waves propagate in a layer like in a two{dim ensional unbound hom ogeneous medium and that \mathcal{D}_{pi} (r;!) = \mathcal{D}_{p} (r;!), the integral on the left hand side of Eq. (14) can be written within the ASA as

Z
$$d^{3}r \mathcal{D} (x;!) = N_{k} \mathcal{D}_{p}$$

$$v = 1$$

where D $_{\rm p}$ is the amplitude of the electric displacement, $n_{\rm p}$ is the refraction vector,

$$n_{\rm p} = \frac{q_{\rm p}}{q_{\rm h}} ; \qquad (16)$$

 q_p the wave vector $(q_0 = 2 = 0)$ refers to the propagation constant in vacuum) and S_{pi} is the radius of the ith atom ic sphere in layer p. A coordingly, the double integral on the right hand side of Eq. (14) reduces to

where E_q is the amplitude of the electric eld in layer q and $\sim^{pi,qj}$ (!; r; r⁰) is the dielectric function \sim (!; r; r⁰) at r 2 $_{pi}$ and r⁰ 2 $_{qj}$.

In the case of visible light the wave vector dependence of the perm ittivity is negligeable. [14] Therefore, after having substituted Eqs. (15) and (17) into Eq. (14), only the rst term in the power series expansions has to be kept, which im mediately leads to

where the inter{ $(p \in q)$, intra{layer (p = q) perm ittivities are given by

$$\sim^{\text{pq}} (!) = \underbrace{P^{(4)^2}_{i p^i i;j}}_{i;j} \underbrace{X^{Z}_{S_{pi}}}_{i;j} \underbrace{Z}_{S_{qj}}_{S_{qj}} dr^0 (r^0)^2 \sim^{\text{pi};qj} (!;r;r^0) :$$

It should be noted that a sim ilar result connecting the static current in layer p to the electric eld in layer q is already known from electric transport theory in inhom ogeneous [39] or layered system s [30]. By using the relation $\mathcal{D}_p = ^p$ (!) \mathbf{E}_p , the layer{resolved perm ittivities p (!) are then solutions of the following system of equations:

$$\sim^{p} (!) E_{p} = \sum_{q=1}^{X^{N}} \sim^{pq} (!) E_{q}; \quad p = 1; :::; N :$$
 (18)

By mapping the inter{ and intra{layer contributions \sim^{pq} (!) to the microscopically exact optical conductivity tensor \sim (!), Eq. (6), onto the corresponding contributions of the permittivity tensor

$$\sim^{pq} (!) = \frac{1}{N} \quad 1 \quad \frac{4 i}{!} \sim^{pq} (!) ;$$
 (19)

one then can establish a well (de ned macroscopical model for the evaluation of Kerr spectra.

C.The 2 2 matrix technique

1. Multiple re ections and optical interferences

In contrast to the two{m edia approach the inclusion of all optical re ections and interferences within a multilayer system assumes that each layer acts as a homogeneous, anisotropic medium between two boundaries and is characterized by a layer{resolved dielectric tensor p (p = 1;:::;N). [18,19]

As a rst step the Fresnel or characteristic equation: [40]

$$n_p^2 n_p n_p n_p \sim^p = 0 (; = x;y;z)$$
 (20)

has to be solved in order to determ ine the normal modes of the electromagnetic waves in a particular layer p. [41] Then by solving the Helmholtz equation for each normal modes, [41]

$$n_{p}^{2}$$
 n_{p} n_{p} n_{p} \sim^{p} $E_{p} = 0$ (; = x;y;z); (21)

the corresponding E_p components of the electric eld in layer p are deduced. A first having obtained the E_p s, the curl M axwell equation [18,19]

$$\widetilde{H}_{p} = \widetilde{n}_{p} \quad \widetilde{E}_{p} ;$$
 (22)

provides the amplitudes of the magnetic elds H_p for each normal mode in layer p. Here the Gaussian system of units has been used, n_p is the refraction vector, as given by Eq. (16), $jn_p \neq n_p$, which in an anisotropic medium is direction and frequency dependent. [40]

Finally, continuity of the tangential components of the electric and the magnetic eld at the boundary between adjacent layers leads to a set of equations, which has to be solved recursively in order to determ ine the magneto {optical coe cients of the layered system, such as, e.g., the surface rejectivity. If no symmetry reduced quantities ~ are used all the previous steps, Eqs. (20) { (22), have to be performed numerically by using { for example { the 2 2 matrix technique of Mansuripur. [18,19]

Most frequently MOKE experiments are performed in polar geometry using normal incidence. Therefore in the following the 2—2 matrix technique of Mansuripur is connect to this particular experimental geometry. This reduction has the advantage that with the exception of the last step in which the surface rejectivity has to be evaluated, all the other steps can be carried out analytically.

In the case of cubic, hexagonal or tetragonal systems and the orientation of the magnetization M_p pointing along the surface normal (z{direction), the layer{resolved permittivity tensor is given by

A ssum ing that $\frac{p}{zz}$ / $\frac{p}{xx}$ (p = 1;:::;N), the error introduced by this simplication { as easily can be shown { is proportional to the dierence $\frac{p}{zz}$ $\frac{p}{xx}$, which in turn is usually small enough to be neglected. If in polar geometry the incidence is normal,

$$n_{px} = n_{py} = 0$$
 for $p = 1; :::; N ;$

the characteristic equation (20) provides four normalmodes of electromagnetic waves in a layer p:

$$n_{pz} = \sum_{x_{xx}}^{p} i_{xy}^{p}$$
:

Two of these four solutions are always situated in the lower half and the other two in the upper half of the complex plane. The rst two solutions, $n_{\rm pz}^{(1)}$ and $n_{\rm pz}^{(2)}$, correspond to a \downward" (negative z {direction}) and the other two, $n_{\rm pz}^{(3)}$ and $n_{\rm pz}^{(4)}$, an \upward" (positive z{direction}) propagation of the electrom agnetic waves. [18,19] These two di erent kinds of cases are given by

$$\stackrel{8}{\gtrless} \mathbf{n}_{pz}^{(1)} = \stackrel{p}{} \frac{}{\stackrel{p}{\swarrow_{xx}} + i \stackrel{p}{\swarrow_{xy}}} \\
\stackrel{?}{\grave{}} \mathbf{n}_{pz}^{(2)} = \stackrel{p}{} \frac{}{\stackrel{p}{\swarrow_{xx}} i \stackrel{p}{\swarrow_{xy}}}$$
(24)

and

$$\stackrel{8}{\approx} n_{pz}^{(3)} = \stackrel{p}{\sim} \frac{p}{\sim_{xx} + i \sim_{xy}^{p}}$$

$$\stackrel{(4)}{\approx} p \frac{p}{\sim_{xx} + i \sim_{xy}^{p}} : \qquad (25)$$

If in a given multilayer system a particular layer p is param agnetic, its perm ittivity tensor p is again of form shown in Eq. (23), with $^p_{xy} = 0$ and $^p_{zz} = ^p_{xx}$. In this case only two beams are propagating, namely those characterized by $n_{pz}^{(1)} = n_{pz}^{(2)} = p_{\overline{x}_x}^{\overline{p}}$ and $n_{pz}^{(3)} = n_{pz}^{(4)} = p_{\overline{x}_x}^{\overline{p}}$. Furthermore, since the vacuum is a homogeneous, isotropic, semilin nite medium, in addition to $n_{xy} = 0$, $n_{xx} = n_{zz} = 1$.

For each solution $n_{pz}^{(k)}$ (k = 1; :::; 4) of the characteristic equation (20), the electric eld must satisfy the Helm holtz equation (21). Because not all of the equations are independent, these can be solved only for two components of the electric eld keeping the third one arbitrary. Therefore, following the strategy proposed by Mansuripur, for beam $1 (n_{pz}^{(1)})$ and beam $3 (n_{pz}^{(3)})$, the corresponding $E_{px}^{(k)}$ are chosen arbitrary, whereas for beam $2 (n_{pz}^{(2)})$ and beam $4 (n_{pz}^{(4)})$, the $E_{py}^{(k)}$ are arbitrary. [18,19] For polar geometry and normal incidence, the solutions of the Helm holtz equation (21) are given in Table I and the corresponding components of the magnetic eld as obtained from Eq. (22) are listed in Table II.

2. Layer{resolved re ectivity matrix

Numbering the layers starting from the rst one on top of the substrate towards the surface, the surface layer has the layer index p=N, see Fig. 1. The 2 2 re ectivity matrix R $_p$ at the lower boundary z_p of layer p is given by: [18,19]

see also the explicit discussion in the Appendix. The tangential components of the electric and magnetic eld at a point z_p^+ just above the boundary z_p are then given by

where according to Tables I and II,

and I is the 2 2 unit matrix.

Using the lower boundary z_{p-1} as reference plane for the four beams in layer p-1, the tangential components of the electric and magnetic eld at a point z_p just below the boundary z_p are of the form

w here

$$C_{p \ 1}^{k,k+1} \quad B \in {}^{i^{\prime} c_{p}^{(k)}} \quad 0 \\ 0 \quad e^{i^{\prime} c_{p}^{(k+1)}} \quad X \qquad k = 1;3;$$
(30)

with

$$\sim_{p-1}^{(k)} q_0 n_{p-1z}^{(k)} d_{p-1}$$
; $k = 1; ...; 4$:

In here $d_p = z_{p+1} = z_p$ is the thickness of layer p, $\mathbf{n}_{p-1z}^{(k)}$ is de ned in Eqs. (24) and (25) and q_0 is the propagation constant in vacuum , see Sect. IV B .

Based on Eqs. (27) and (29), the continuity of the tangential components of the electric and magnetic eld on the boundary $z_{\rm p}$ implies that

such that by elim inating the electric eld vectors, one im m ediately gets

$$D_{p} 1 (1 + R_p) = B_p^{12} (I R_p)$$
;

where

$$D_{p 1} B_{p 1}^{12} C_{p 1}^{12} C_{p 1}^{34} R_{p 1} C_{p 1}^{12} + C_{p 1}^{34} R_{p 1}^{1} :$$
 (31)

R $_{\rm p}$ is therefore given in term s of R $_{\rm p}$ $_{\rm 1}$ by the following simple recursion relation:

$$R_p = B_p^{12} + D_{p1}^{1} B_p^{12} D_{p1} p = 1; :::; N :$$
 (32)

In order to determ ine the re-ectivity matrix R_N of the surface layer, one has to evaluate all re-ectivity matrices R_p for all layers below the surface layer. This requires to start the iterative procedure at the rst layer (p=1) on top of the substrate. But in order to calculate R_1 , one needs to know the 2-2 matrix D_0 corresponding to the substrate, see Eq. (32). This in turn, according to Eq. (31) is only the case, if the re-ectivity matrix R_0 of the substrate is available. In order to achieve this, one has to formulate the tangential components of the electric and magnetic eld at z_1 by taking into account that the substrate is a semi{in nite bulk without any boundaries and hence $R_0=0$. [18,19] Thus $D_0=B_0^{12}$, which according to Eq. (28) requires to specify the permittivity of the substrate.

3. Surface re ectivity matrix

In the vacuum region, since $\gamma_{xx} = 1$, $\gamma_{xy} = 0$, one has to deal with the superposition of only two beams, namely that of the incident and rejected electromagnetic waves. These beams are related through the surface rejectivity matrix R surf such that for polar geometry and normal incidence,

see the Appendix. Thus the tangential components of the electric and magnetic eld at a point z_{N+1}^+ , namely just above the interface between the vacuum and the surface, are given by

w here

$$B_{\text{vac}}^{12} = \begin{bmatrix} B & 0 & 1 & 0 & 1 \\ A & A & A & B_{\text{vac}}^{34} = \begin{bmatrix} B & 0 & 1 & C \\ A & A & A & B_{\text{vac}}^{34} & A & B_{\text{vac$$

A coording to Eqs. (29) and (34), the continuity of the tangential components of the electric and magnetic elds at the vacuum and surface layer interface, $z_{N+1}=0$, can be written as

By elim inating from this system of equations the electric eld vectors, it follows that

$$F_N$$
 (1 + R_{surf}) = B_{vac}^{12} + B_{vac}^{34} R_{surf} ;

where

$$F_N = B_N^{12} C_N^{12} = C_N^{34} R_N = C_N^{12} + C_N^{34} R_N = {}^{1} A^{-1} = D_N A^{-1}$$
: (36)

Thus for the surface re ectivity matrix one obtains

$$R_{surf} = F_{N} B_{vac}^{34} B_{vac}^{12} F_{N}$$
: (37)

The surface re-ectivity matrix R_{surf} is therefore of the form given in Eq. (33), see also Appendix. In spherical coordinates, one immediately obtains the complex re-ectivity of the right and left handed circularly polarized light as

$$r = r_{xx} \quad ir_{xy}$$
;

which in turn determ ines the Kerr rotation angle $_{\rm K}$ and ellipticity $_{\rm K}$, see Eqs. (9) and (10).

4. Self{consistent layer{resolved perm ittivities

In order to calculate for a homogeneous, anisotropic layer p the corresponding dielectric tensor (23) from the inter{ and intra{layer permittivities de ned in Eq. (19), the following linear system of equations

has to be solved, see Eq. (18). Here for $E_{\rm p}$ one can take the following Ansatz:

where due to Eq. (30),

$$C_{p}^{k;k+1} \stackrel{\frac{1}{2}}{=} B \stackrel{\text{iq}_{0} \hat{\mathbf{r}}_{pz}^{(k)} \frac{d_{p}}{2}}{0} 0 K = 1;3:$$

By using the continuity equation of the tangential components of the electric eld at the boundaries, see Eqs. (27), (29) and (34), one then obtains the layer resolved permittivities as a weighted sum of the inter and intra layer permittivities de ned in Eq. (19):

where

$$W_{pq} = A$$
 W_{q+k}
 W_{p+k}
 W

with

$$W_{p+k} = (I + R_{p+k}) C_{p+k}^{12} + C_{p+k}^{34} R_{p+k}^{1}$$
; $k = 1; ...; N p;$

and

$$W_{p} = C_{p}^{12} + C_{p}^{34} + C_{p}^{34} + C_{p}^{12} + C_{p}^{34} + C_{p}^{3$$

Because the 2 2 m atrices W $_{p+k}$ contain R $_p$, C_p^{12} and C_p^{34} , which in turn depend on layer{resolved perm ittivities p (!), Eq. (38) has to be solved iteratively.

The self(consistent procedure can be started by putting all 2 weighting matrices W $_{pq}$ in Eq. (39) to unity, i.e., by neglecting the phase dierences of the electromagnetic waves between the lower and upper boundaries in each layer p,

$$\sim^{p} (!)^{(0)} = \sum_{q=1}^{N} \sim^{pq} (!) :$$
 (40)

These quantities \sim^p (!) $^{(0)}$ can be used to calculate R $_p^{(0)}$ in term sofEqs. (31) and (32). Improved layer{resolved permittivities follow then from Eq. (38). This iterative procedure has to be repeated until the difference in the old and new layer{resolved permittivity of layer p is below a numerical threshold $_p$,

max
$$\sim^{p} (!)^{(i+1)} \sim^{p} (!)^{(i)}$$
 "p: (41)

V.RESULTS AND DISCUSSIONS

>From experiments is known that Pt substrates prefer an fcc(111) orientation. [42] Therefore in the present contribution, the calculations for the layered system $s CoPt_5 Pt(111)$ and $Pt_3 CoPt_5 Pt(111)$ have been performed, with ve Pt layers serving as bu er [43] to bulk fcc Pt.

The Ferm i level in Eqs. (3) and (4) is that of param agnetic fcc Pt bulk (lattice param eter of 7.4137 a.u.), which also serves as parent lattice, [43] i.e., no layer relaxation is considered.

A.Param agnetic fcc(111) Pt substrate

As mentioned above in order to determ ine the surface rejectivity the permittivity tensor of the sem i(in nite substrate has to be evaluated. As can be seen from Fig. 2, the xx{element of the permittivity tensor of the fcc(111) Pt substrate shows a rather simple photon energy dependence. The real part of the permittivity γ_{xx} (!) has a peak around 1 eV, while the imaginary part of γ_{xx} (!) exhibits an almost perfect hyperbolic frequency dependence. The strong decay of γ_{xx} (!) for photon energies in the vicinity of the static limit (! = 0) can be easily understood in terms of the Eqs. (19) and (40), see also Ref. [13]: for ! ! 0 the real part of γ_{xx} (!) must tend to minus in nity whereas the imaginary part has to decrease.

The xy {element of the permittivity tensor for fcc{Pt(111) is identical zero over the whole range of optical frequencies, a functional behavior that of course does not need to be illustrated.

B. Self(consistent layer(resolved permittivities

In terms of the substrate and the zeroth order layer{resolved perm ittivities, see Eq. (40), the iterative determination of the surface rejectivity matrix described above, provides also self{consistent, layer{resolved permittivities $^p_{xx}$ (!) in a very eigent manner: in less than we iterations an accuracy of $^n_p = 10^{-13}$ for each layer p, see Eq. (41), can be achieved.

In order to illustrate this procedure, in Fig. 3 the imaginary part of the relative dierence between the self(consistent and zeroth order layer(resolved xx{element of the permittivity tensor for $CoPt_5Pt(111)$ with and without Pt cap layers is displayed.

This relative di erence is to be viewed as the relative error made by using according to Eq. (40) the 2 2 m atrix technique with zeroth order layer{resolved permittivities. As can be seen from Fig. 3, this relative error is layer, frequency and system dependent. The higher the photon energy and the bigger the layered system the less exact are the zeroth order layer{ resolved permittivities. However, for relatively small layered systems, the relative error made by using only zeroth order permittivities is typically below 5% for γ_{xx} (!) and less than 20% for γ_{xy} (!). However, the resulting relative error in the Kerr rotation angle and the ellipticity as calculated by comparing the spectra corresponding to the self{consistent} and to the zeroth order

layer{resolved perm ittivities, is always less than 1%. Therefore, Eq. (40) can be considered as reasonably good approximation for layer{resolved perm ittivities.

C.Polar Kerre ect for norm al incidence

The systems investigated in here refer to a Comono{layer on the top of a fcc{Pt(111)} substrate, considering also the case of three Pt cap layers. As already mentioned, ve Pt layers serve as buer to the sem i{in nite host in order to ensure that the induced magnetic moments decrease monotonously to zero into the param agnetic Pt substrate.

The ab{initio Kerr spectra obtained from self{consistent layer{resolved perm ittivities by applying the 2 2 matrix technique are shown in Fig. 4. Usually, in experiments Pt cap layers are deposited on top of Co in order to prevent the oxidation of the surface. [44] By performing a separate, magnetic anisotropy calculation, [43] we have found that CoPt(111) exhibits perpendicular magnetization only in the presence of Pt cap layers. Therefore, for the polar Kerr spectra of the $CoPt_5Pt(111)$ system shown in Fig. 4 the polar geometry, namely the perpendicular orientation of the magnetization is imposed.

A nalyzing in Fig. 4 the Kerr spectra of the capped and that of the uncapped systems, several dierences can be observed. The negative peak in the Kerr rotation angle $_{\rm K}$ at 3 eV in the spectrum of CoPt $_{\rm 5}$ Pt(111) almost disappears from the spectrum in the case of the capped layered system. In the Kerr ellipticity the zero location at 2.8 eV observed for the uncapped system is shifted to 2.5 eV for the capped system system and simultaneously the infrared (IR) positive peak is shrunk and moved towards lower photon energies. Besides these features, the sign of the ultraviolet (UV) peak in both, the Kerr rotation and ellipticity spectra is changed, when the Co surface layer is capped. This particular feature can also be observed in the Kerr spectra obtained by using the two{media approach, see Fig. 5. In the two{media Kerr rotation spectrum, the negative IR peak at 2 eV in CoPt $_{\rm 5}$ Pt(111) is shifted to about 1 eV in case of the capped system.

Comparing the spectra in Fig. 4 with those in Fig. 5, it is evident that the theoretical Kerr spectra depend indeed on the macroscopic model used to describe the propagation of electromagnetic waves in the system. Because the systems investigated in here are much smaller

than those used in experim ents, [44,45] a strict quantitative comparison with experim ental data cannot be made. However, a qualitative comparison based on the well(known, general features of the Copt experimental Kerr spectra is still possible: [45] the Kerr rotation angle shows (a) a small negative IR peak at 1.5 eV, which decreases in amplitude with decreasing Cothickness, and (b) a high and broad negative UV peak, which moves from 4.1 eV to 3.9 eV for increasing Cothickness. The Kerr ellipticity is characterized by (a) a shift of the zero location at 1.5 eV (pure Colm) to 3.7 eV with decreasing Cothickness, (b) a positive peak around 3 eV and (c) a shift of the minimum at 4.9 eV in pure Colm towards higher photon energies.

In the Kerr rotation spectra of the capped system shown in Fig. 4, there is no negative IR peak around $1.5 \, \text{eV}$, but a negative UV exists at $5.5 \, \text{eV}$. The Kerr ellipticity spectra of the capped system in Fig. 4, has a zero location at $2.5 \, \text{eV}$ and positive peaks show up at 0.5, 3.5, 4 and 5 eV. These features suggest that in the case of Pt₃ CoPt_5 Pt(111) the Kerr spectra obtained by applying the 2 2 m atrix technique are typical for CoPt layered systems.

A sim ilar investigation of the Kerr rotation spectra in Fig. 5, reveals that for the capped system there are two negative IR peaks at 1, 15 eV and a negative UV peak around 5 eV. The Kerr ellipticity for the capped system in Fig. 5 shows a zero location at 1 eV (1.5 eV in case of a pure Co lm), two positive peaks at 4 and 5 eV and a small negative peak around 3 eV. All these features make the Kerr spectra of Pt₃ $\$ CoPt₅ $\$ Pt(111) described via the two{media approach to resemble those of a pure Co lm rather than those of a CoPt layered system.

Previous results obtained by applying the 2 2 m atrix technique using as substrate permittivity that of the last Pt{layer below the Co one, [46] have shown similar characteristics in the Kerr spectra. Hence, these features cannot be ascribed to the presence of the substrate. In an other contribution, [31] it was shown that the optical conductivity of these systems is dominated by the contributions arising from the polarized Pt{layers. Therefore, the pure Co lm {like spectra obtained for Pt₃ CoPt_5 Pt(111) within the two{media approach can be seen as an indication that a layered system cannot be approximated by a homogeneous medium in which no optical refections or interferences occur.

VI.SUM M ARY

We have used the 2 2 m atrix technique for the most frequently used experimental set {up, namely for polar geometry and normal incidence. This technique allows one to account for all multiple rejections and optical interferences in a semi{in nite layered system. The Kerr rotation angle and ellipticity can be directly obtained from the iteratively calculated surface rejectivity matrix, which in turn can be used to determine layer{resolved permittivities self{consistently. For free surface of layered systems realistic ab{initio Kerr spectra are obtained using the inter{and intra{layer conductivities as given by Luttinger's formula within the spin{polarized relativistic screened Korringa{Kohn{Rostoker method.}

A comparison of the theoretical Kerr spectra of CoPt₅ Pt(111) and Pt₃ CoPt_5 Pt(111) as obtained by applying the 2 2 m atrix technique and the two{media approach indicates that the former technique provides typical results for layered systems, whereas the later approach tends to generate spectra specic for homogeneous lms on top of a substrate.

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APPENDIX: SYM M ETRY OF REFLECTIVITY M ATRICES

Since for a sem i{in nite substrate, $R_0 = 0$, $D_0 = B_0^{12}$, with B_0^{12} as given by Eq. (28), according to Eq. (32), the re-ectivity matrix of the rst layer on top of the substrate is given by

$$R_{1} = \begin{bmatrix} B & \mathbf{r}_{1} & 0 & C \\ 0 & & A & \mathbf{r}_{1} \end{bmatrix}$$

w here

Assuming that allp 1 re ectivity matrices are of this diagonal form, namely

$$R_{j} = \begin{bmatrix} B & r_{j} & 0 & C \\ 0 & A & J \end{bmatrix} = 1; ::: ; (p 1) ;$$

by taking into account Eqs. (28) and (30), Eq. (31) im m ediately yields

$$D_{p 1} = \begin{bmatrix} B & i\vec{\Omega}_{p 1} & \vec{\Omega}_{p 1}^{0} & C \\ & & A ; \\ \vec{\Omega}_{p 1} & i\vec{\Omega}_{p 1}^{0} \end{bmatrix}$$

where

The re-ectivity matrix of layer p as obtained from the recursion relation (32) is found to be also diagonal

$$R_{p} = \begin{cases} 0 & 1 \\ R_{p} & 0 \\ 0 & A \end{cases}$$

where

i.e., all the layer{resolved re-ectivity m atrices R $_j$ (j=1; :::; N) are diagonal m atrices as was anticipated in Eq. (26).

In term s of the diagonal re-ectivity m atrix of the surface layer R $_{\rm N}$, and A and B $_{\rm N}^{12}$ as given by Eq. (28), Eq. (36) reduces to

$$F_{N} = \frac{1}{2} \begin{bmatrix} 0 & 1 \\ if_{N} & f_{N}^{0} & C \\ f_{N}^{0} & if_{N} & \end{bmatrix};$$

w here

By using F_N together with the matrices de ned in Eq. (35) in Eq. (37), the resulting surface re ectivity matrix is of the form anticipated in Eq. (33), i.e.

$$R_{surf} = B \qquad \begin{array}{c} \mathbf{r}_{xx} & \mathbf{r}_{xy} & \mathbf{c} \\ \mathbf{r}_{xy} & \mathbf{r}_{xx} \end{array} ;$$

w here

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TABLES

k	1	2	3	4
E _{px} (k)	arbitrary	iE _{py} (2)	arbitrary	iE _{py} (4)
E _{py} (k)	$iE_{px}^{(1)}$	arbitrary	iE _{px} (3)	arbitrary
E _{pz} (k)	0	0	0	0

TABLE I. Solutions of the Helm holtz equation (21) for polar geom etry and normal incidence neglecting the dierence in the diagonal elements of the layer (resolved permittivity. $E_p^{(k)}$ is the amplitude of the electriceld in layer p for beam k.

k	1	2	3	4
H (k)	$iE_{px}^{(1)}$ $\frac{p}{\sqrt{2}x + ir_{xy}^p}$	$E_{py}^{(2)}$ $\frac{p}{\gamma_{xx}^p}$ $i\gamma_{xy}^p$	$iE_{px}^{(3)}$ $\frac{p}{\sqrt{2}x + i\sqrt{2}y}$	$E_{py}^{(4)}$ $\frac{p}{\sim_{xx}}$ $i_{\sim_{xy}}^{p}$
Н ^(k)	$E_{px}^{(1)}$ $\frac{p}{\sim_{xx}^p + i\sim_{xy}^p}$	$iE_{py}^{(2)}$ $\frac{p}{\sqrt{2}}$ $i\frac{p}{\sqrt{2}}$	$E_{px}^{(3)} \frac{p}{\sqrt[p]{x_x} + i\sqrt[p]{x_y}}$	$iE_{py}^{(4)}$ $\frac{p}{\sqrt{x}}$ ix_y
H (k)	0	0	0	0

TABLE II. Solutions of the curl M axwell equation (22) for polar geometry and normal incidence neglecting the dierence in the diagonal elements of the layer{resolved permittivity p. H p is the amplitude of the magnetic eld in layer p for beam k.

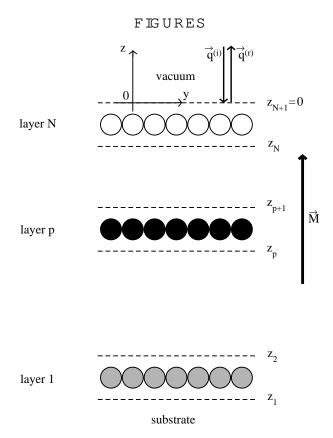


FIG.1. The macroscopic model used for a layered system within the 2-2 matrix technique for polar geometry and normal incidence. The x axis is perpendicular to the plane of the gure, $q^{(i)}$ is the incident and $q^{(r)}$ is the rejected wave vector. M' denotes the total spontaneous magnetization of the system.

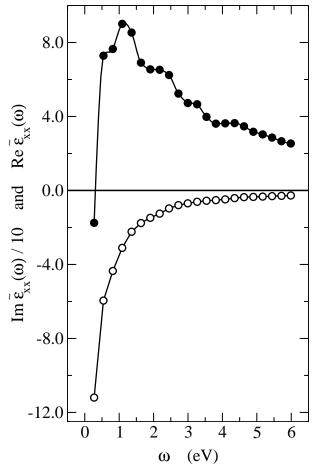


FIG. 2. The perm ittivity for fcc(111){Pt bulk as a function of the photon energy!. The real part of the perm ittivity is denoted by full circles, the imaginary part by open circles.

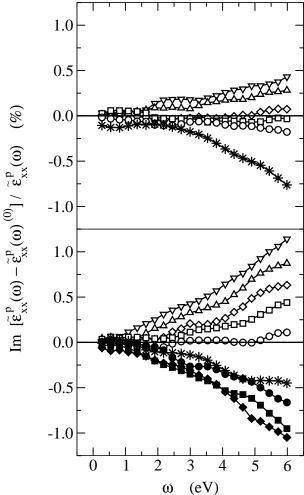


FIG. 3. Imaginary part of the relative di erence between the self(consistent and zeroth order layer(resolved xx{element of the permittivity tensor as a function of the photon energy! for fcc $CoPt_5Pt(111)$ (top) and $Pt_3PcoPt_5Pt(111)$ (bottom). The data represented by full (open) circles correspond to the rst, squares to the second and diamonds to the third Pt layer on top of (under) the Co layer (stars). Open triangles down (up) denote the rst (second) Pt layer data on top of a param agnetic fcc(Pt(111) substrate.

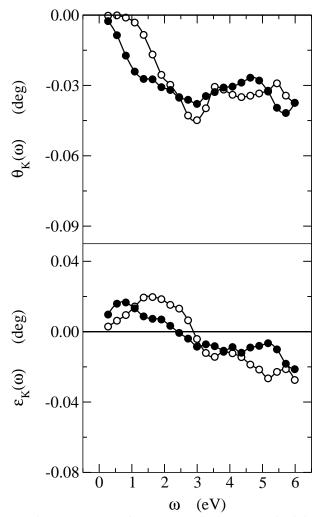
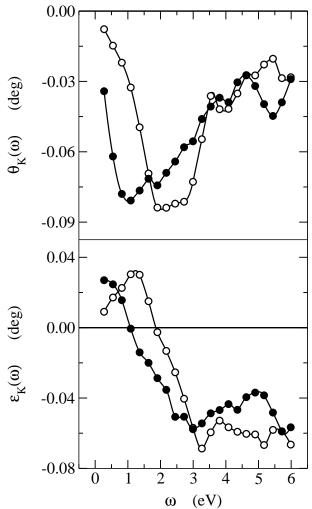


FIG. 4. The magneto {optical K err rotation angle $_{\rm K}$ (!) and ellipticity $_{\rm K}$ (!) for polar geometry and normal incidence as a function of the photon energy! obtained by applying the 2 2 matrix technique for the self{consistent layer{resolved permittivities of fcc CoPt₅ Pt(111) (open circles) and Pt₃ CoPt_5 Pt(111) (full circles).



 $\omega \quad (eV)$ FIG.5. As in Fig.4, but here the Kerr spectra was obtained by applying the two{media approach for fcc CoPt5 Pt(111) (open circles) and Pt3 PcPt5 Pt(111) (full circles).